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FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT PATENT AND TRAD	OF COMMERCE EMARK OFFICE	ATTY. DOCKET NO. :				577930		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT: Friedrich LUELLAU ET AL						
(Use several sheets if necessary)				FILING DATE:		GROUP:				
			U.S.	PATENT DOCUMENTS						
'EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	C	CLASS SUBCL		FILING DATE IF APPROPRIATE		
/S.C./	AA	6,249,306 B1	06/2001	Isono et al.(ISR)						
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		Interna	ational	Search Report						

EXAMINER: Initial if reference considered, whether or not citati form with next communication to applicant. n is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this

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/Sunil Chacko/